	Application No.	Applicant(s)
Notice of Allowability	10/753,460	SUENAGA ET AL.
	Examiner	Art Unit
	Robert Rose	3723
The MAILING DATE of this communication appe All claims being allowable, PROSECUTION ON THE MERITS IS herewith (or previously mailed), a Notice of Allowance (PTOL-85) NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT RI	(OR REMAINS) CLOSED in this ap or other appropriate communicatior GHTS. This application is subject to	plication. If not included in will be mailed in due course. THIS
1. This communication is responsive to 4/9/04,8/20/04.		
2. X The allowed claim(s) is/are <u>1-20</u> .		
3. The drawings filed on 09 January 2004 are accepted by the	e Examiner.	
 4. Acknowledgment is made of a claim for foreign priority un a) All b) Some* c) None of the: 1. Certified copies of the priority documents have 2. Certified copies of the priority documents have 3. Copies of the certified copies of the priority documents have International Bureau (PCT Rule 17.2(a)). 	been received. been received in Application No	
* Certified copies not received:		
Applicant has THREE MONTHS FROM THE "MAILING DATE" of noted below. Failure to timely comply will result in ABANDONM THIS THREE-MONTH PERIOD IS NOT EXTENDABLE.		complying with the requirements
 A SUBSTITUTE OATH OR DECLARATION must be submi INFORMAL PATENT APPLICATION (PTO-152) which give 	tted. Note the attached EXAMINER is reason(s) why the oath or declara	'S AMENDMENT or NOTICE OF tion is deficient.
 CORRECTED DRAWINGS (as "replacement sheets") musical including changes required by the Notice of Draftsperson 1) hereto or 2) to Paper No./Mail Date (b) including changes required by the attached Examiner's Paper No./Mail Date Identifying indicia such as the application number (see 37 CFR 1. each sheet. Replacement sheet(s) should be labeled as such in the deposed attached Examiner's comment regarding REQUIREMENT Formula (see 2.2). 	on's Patent Drawing Review (PTO- s Amendment / Comment or in the C 84(c)) should be written on the drawing he header according to 37 CFR 1.121(sit of BIOLOGICAL MATERIAL r	Office action of ngs in the front (not the back) of d). nust be submitted. Note the
 Attachment(s) 1. ☑ Notice of References Cited (PTO-892) 2. ☐ Notice of Draftperson's Patent Drawing Review (PTO-948) 3. ☑ Information Disclosure Statements (PTO-1449 or PTO/SB/06 Paper No./Mail Date see item 9. 4. ☐ Examiner's Comment Regarding Requirement for Deposit of Biological Material . 	6. ☐ Interview Summary Paper No./Mail Da 8), 7. ☐ Examiner's Amendr	te nent/Comment ent of Reasons for Allowance

U.S. Patent and Trademark Office PTOL-37 (Rev. 1-04) Application/Control Number: 10/753,460 Page 2

Art Unit: 3723

REASONS FOR ALLOWANCE

1. Receipt is acknowledged of Applicant's Preliminary Amendment, filed January 9, 2004.

- 2. Receipt is acknowledged of Applicant's Prior Art Statements, filed Aprl 9, 2004, and August 20, 2004, respectively.
- 3. The following is an examiner's statement of reasons for allowance:

Applicant's invention relates to a polishing composition having a specified particle size distribution, and a polishing method for reducing "<u>microwaviness</u>" as defined in the specification as having both short wavelength(50um to 500um) and long wavelength(500um to 5mm) of the roughness, to produce a magnetic disk substrate of improved smoothness, allowing lowered magnetic head flying heights.

While conventional silica compositions are employed, the particle size distribution is adjusted such that the formulas set forth in claim 1 are satisfied. The average particle size on the number basis, and standard deviation on the number basis are satisfied in addition to satisfying a relationship between the particle size and cumulative volume frequency within the specified range of particle size. Formula(1) is an index showing the spread of the particle size distribution of the silica particles, and is satisfied from the viewpoint of improving the polishing rate. Formulas(2) and (3) are indicies each showing a ratio of silica particles existing therein. These formulas are satisfied from the viewpoint of improving the microwaviness of the substrate, thereby improving the smoothness of the finished surface.

Application/Control Number: 10/753,460 Page 3

Art Unit: 3723

None of the references cited satisfy the conditions set forth in the formulas of independent claim 1. The closest prior art, Japan 2002-30274, achieves a reduced average surface waviness, however, the reduction of short wavelength and long wavelength waviness are not addressed. Other art cited of interest also show conventional slurries with average particle size distributions which are not adjusted so as to address the reduction in microwaviness of the final product.

- 4. Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."
- 5. Any inquiry concerning this communication or earlier communications from the examiner should be directed to Robert Rose whose telephone number is (571) 272-4494. The examiner can normally be reached on 8:00-5:30.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Joseph Hail can be reached on (571) 272-4485. The fax phone number for the organization where this application or proceeding is assigned is 703-872-9306.

Art Unit: 3723

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

Robert Rose Primary Examiner Art Unit 3723

Rr

February 7, 2005.